

**Notice of References Cited**

Application/Control No.

09/715,783

Applicant(s)/Patent Under  
Reexamination  
BAIRD ET AL.

Examiner

Christopher R Nalevanko

Art Unit

2611

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,208,376	03-2001	Tanaka et al.	348/153
	B	US-2002/0167590	11-2002	NAIDOO et al.	348/155
	C	US-2003/0112335	06-2003	Strandwitz et al.	348/211.2
	D	US-6,317,164	11-2001	Hrusecky et al.	348/581
	E	US-6,384,862	05-2002	Brusewitz et al.	348/211.99
	F	US-6,333,750	12-2001	Odryna et al.	345/629
	G	US-6,041,361	03-2000	Wilson et al.	709/253
	H	US-6,628,325	09-2003	Steinberg et al.	348/211.1
	I	US-6,697,105	02-2004	Kato et al.	348/211.6
	J	US-6,529,234	03-2003	Urisaka et al.	348/211.99
	K	US-2001/0056579	12-2001	Kogane et al.	725/105
	L	US-6,091,771	07-2000	Seeley et al.	375/240
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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